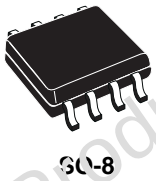
STS15N4LLF5

N-channel 40 V, 0.00625 Ω, 15 A, SO-8 STripFET™ Power MOSFET

Features

Type	V_{DSS}	$R_{DS(on)}$ max.	I_D
STS15N4LLF5	40 V	< 0.0076 Ω	15 A

- Optimal $R_{DS(on)}$ x Q_g trade-off @ 4.5 V
- Conduction losses reduced
- Switching losses reduced



Applications

- Switching application

Description

This STripFET™V Power MOSFET technology is among the latest improvements, which have been especially tailored to achieve very low on-state resistance providing also one of the best-in-class figure of merit (FOM).

Figure 1. Internal schematic diagram

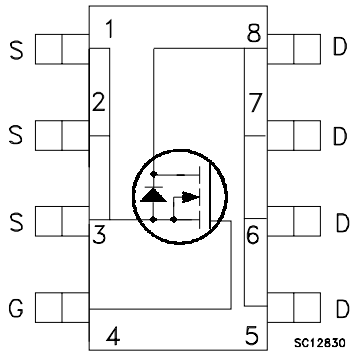


Table 1. Device summary

Order code	Marking	Package	Packaging
STS15N4LLF5	15C4L	SO-8	Tape and reel

Obsolete Product(s) - Obsolete Product(s)

Contents

1 Electrical ratings 3

2 Electrical characteristics 4

2.1 Electrical characteristics (curves) 6

3 Test circuits 8

4 Package mechanical data 9

5 Revision history 11

Obsolete Product(s) - Obsolete Product(s)

1 Electrical ratings

Table 2. Absolute maximim ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage (V_{GS} = 0)	40	V
V_{GS}	Gate-source voltage	± 16	V
V_{GS} (1)	Gate- source voltage	±18	V
I_D	Drain current (continuous) at T_C = 25 °C	15	A
I_D	Drain current (continuous) at T_C = 100 °C	10	A
I_{DM} (2)	Drain current (pulsed)	63.6	A
P_{TOT}	Total dissipation at T_C = 25 °C	3	W
E_{AS} (3)	Single pulse avalanche energy	109	mJ

1. Guaranteed for test time ≤ 15ms
2. Pulse width limited by Tjmax
3. Starting T_j = 25 °C, I_D = 7.5 A, V_{DD} = 25 V

Table 3. Thermal resistance

Symbol	Parameter	Value	Unit
$R_{thj\text{-}pcb}$ (1)	Thermal resistance junction-pcb max	47	°C/W
T_l	Maximum lead temperature for soldering	-55 to 150	°C
T_{stg}	Storage temperature	-55 to 150	°C

1. When mounted on FR-4 board with 1 inch^2 pad, 2oz of Cu and t < 10 sec

Obsolete Product(s) - Obsolete Product(s)

2 Electrical characteristics

(T_J = 25 °C unless otherwise specified)

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	I_D = 250 µA, V_{GS}= 0	40			V
I_{DSS}	Zero gate voltage drain current (V_{GS} = 0)	V_{DS} = max rating, V_{DS} =max rating @125°C			10 100	µA µA
I_{GSS}	Gate body leakage Current (V_{DS} = 0)	V_{GS} = ±16 V			±200	nA
$V_{GS(th)}$	Gate threshold voltage	V_{DS}= V_{GS}, I_D = 250 µA	1			V
$R_{DS(on)}$	Static drain-source on resistance	V_{GS}= 10 V, I_D= 7.5 A V_{GS}= 4.5 V, I_D= 7.5 A		0.00625 0.0076	0.0067 0.0083	Ω Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss} C_{oss} C_{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V_{DS} = 25 V, f=1 MHz, V_{GS}= 0	-	1570 257 32	-	pF pF pF
Q_g Q_{gs} Q_{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} = 15 V, I_D = 18 A V_{GS} = 4.5 V *(see Figure 14)*	-	12.9 3.9 5.3	-	nC nC nC
R_G	Gate input resistance	f=1 MHz Gate DC Bias = 0 Test signal level = 20 mV open drain	-	1.5	-	Ω

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ t_r	Turn-on delay time Rise time	V_{DD} = 15 V, I_D = 9 A, R_G = 4.7 Ω, V_{GS} = 10 V *(see Figure 16)*	-	14 42	-	ns ns
$t_{d(off)}$ t_f	Turn-off delay time Fall time		-	37 5.2	-	ns ns

Obsolete Product(s) - Obsolete Product(s)

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD} I_{SDM} (1)	Source-drain current Source-drain current (pulsed)		-		18 72	A A
V_{SD} (2)	Forward on voltage	I_{SD} = 18 A, V_{GS} = 0	-		1.2	V
t_{rr} Q_{rr} I_{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD} = 18 A, V_{DD} = 25 V, di/dt = 100 A/µs, Tj = 150 °C *(see Figure 15)*	-	27.2 24.5 1.8		ns nC A

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300µs, duty cycle 1.5%

Obsolete Product(s) - Obsolete Product(s)

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

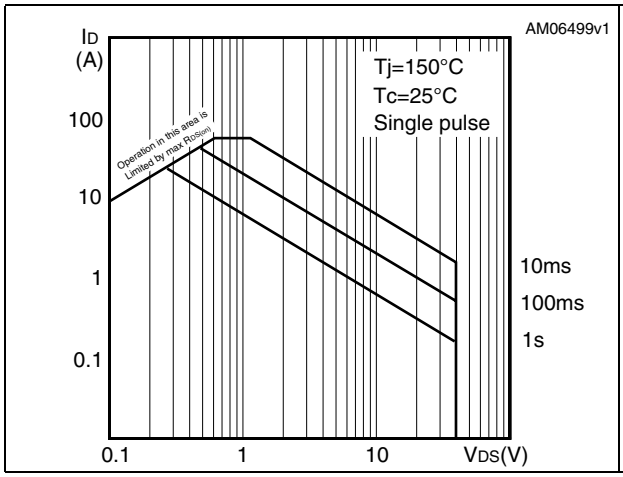


Figure 3. Thermal impedance

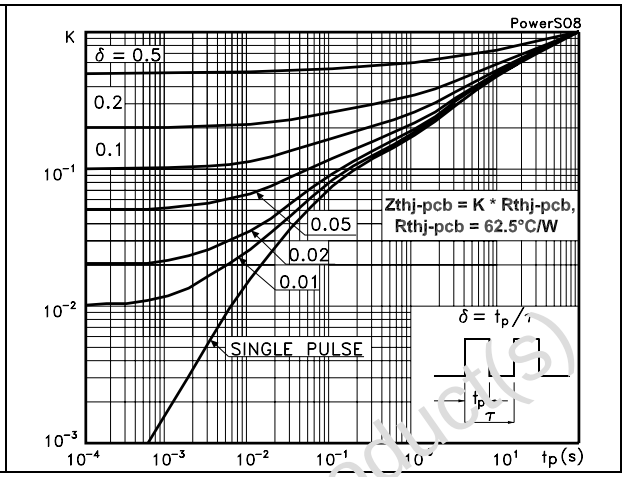


Figure 4. Output characterisics

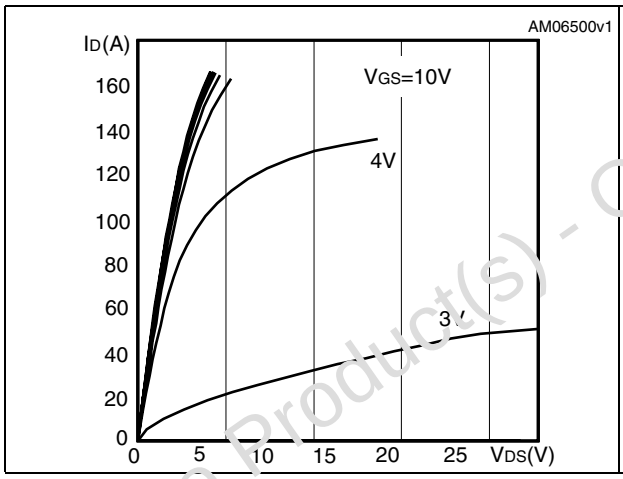


Figure 5. Transfer characteristics

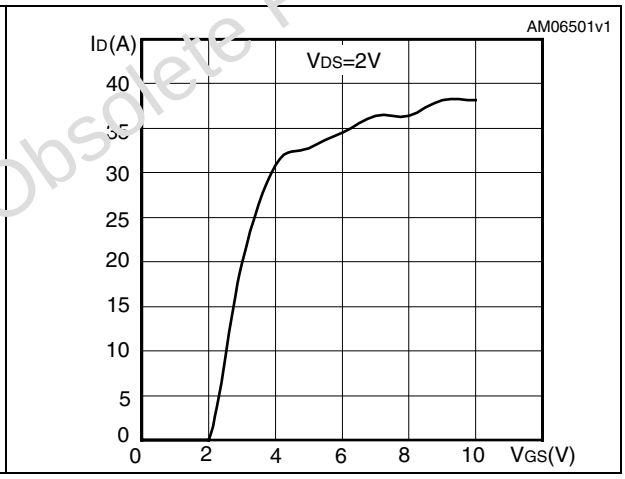


Figure 6. Normalized B_{VDSS} vs temperature

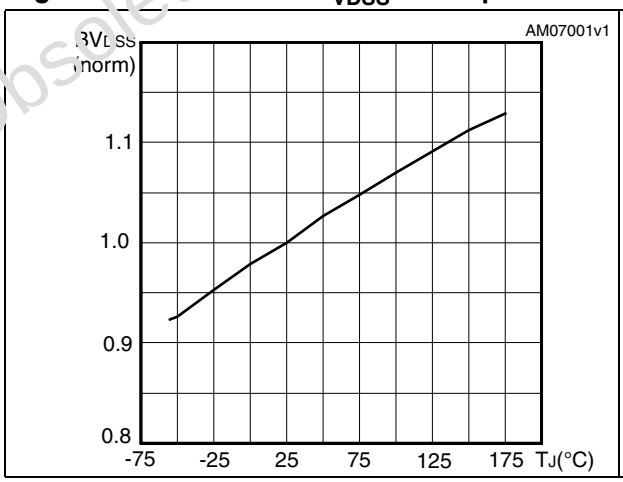
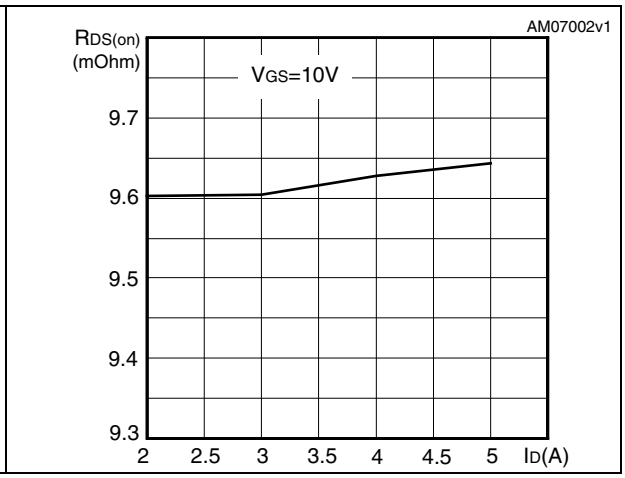


Figure 7. Static drain-source on resistance



Obsolete Product(s) - Obsolete Product(s)

Figure 8. Gate charge vs gate-source voltage

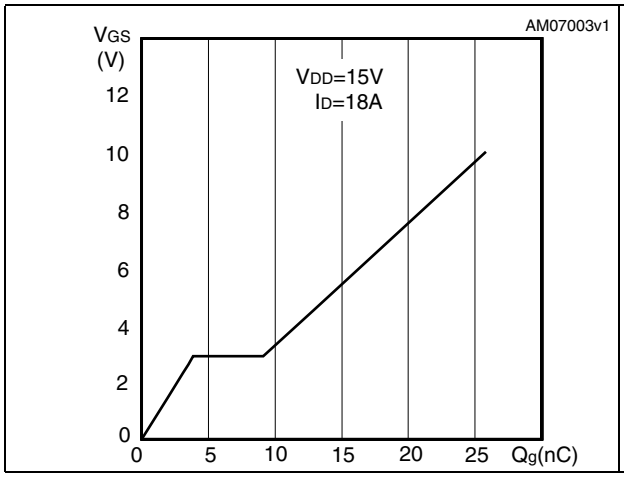


Figure 9. Capacitance variations

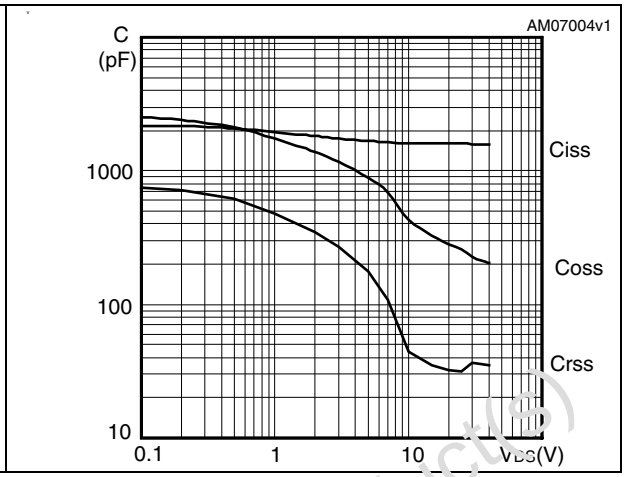


Figure 10. Normalized gate threshold voltage vs temperature

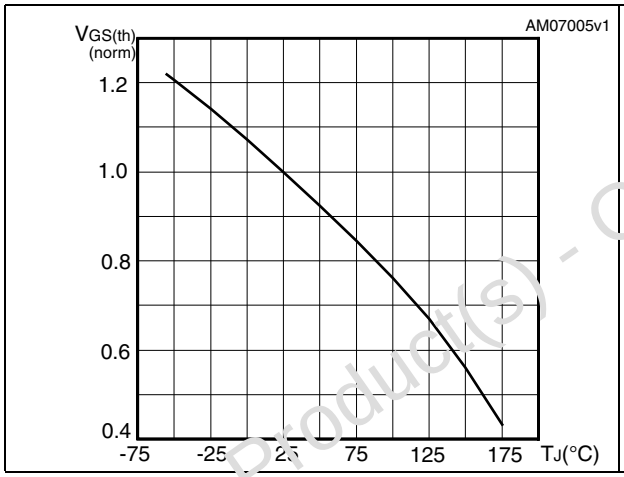


Figure 11. Normalized on resistance vs temperature

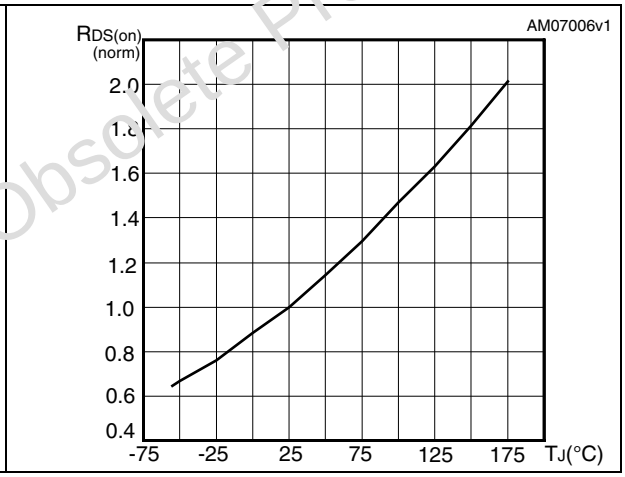
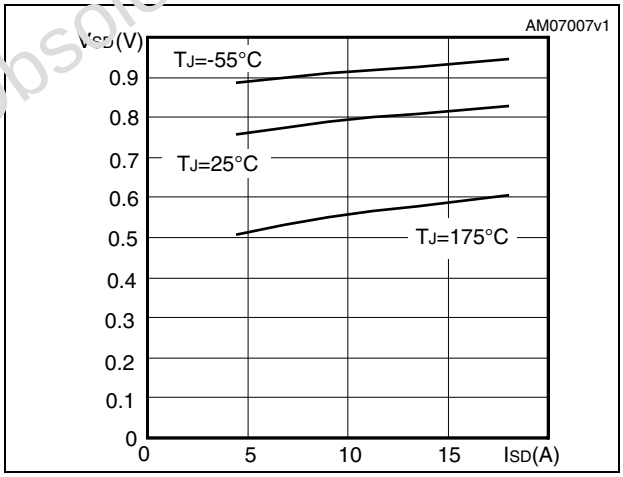


Figure 12. Source-drain diode forward characteristics



Obsolete Product(s) - Obsolete Product(s)

3 Test circuits

Figure 13. Switching times test circuit for resistive load

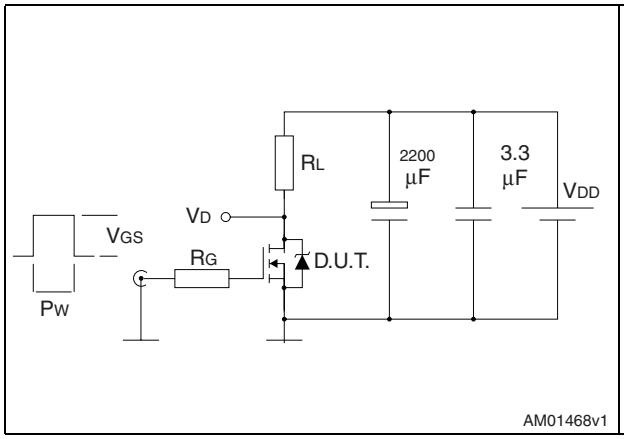


Figure 14. Gate charge test circuit

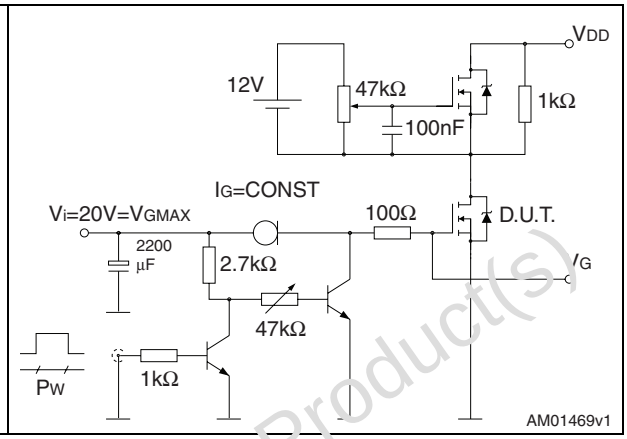


Figure 15. Test circuit for inductive load switching and diode recovery times

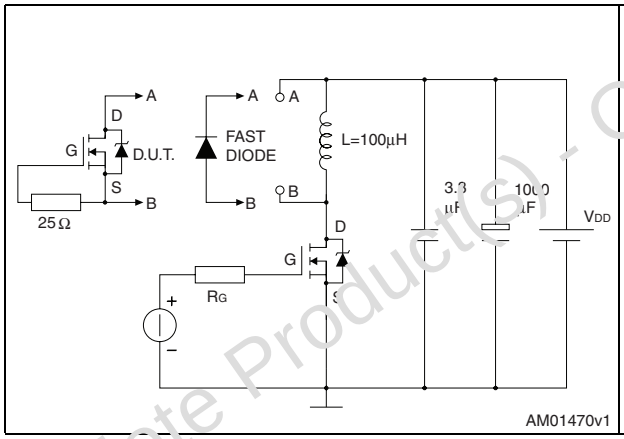


Figure 16. Unclamped inductive load test circuit

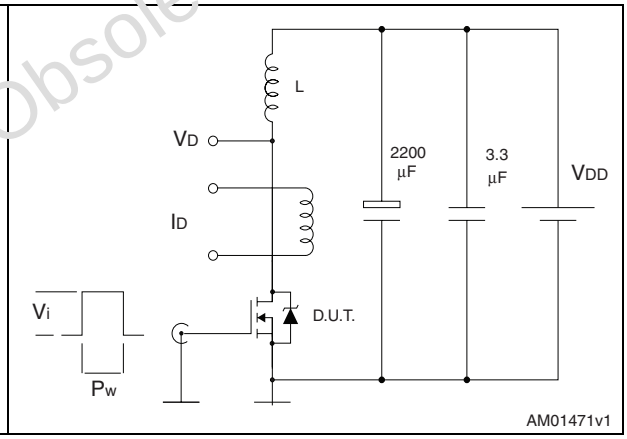


Figure 17. Unclamped inductive waveform

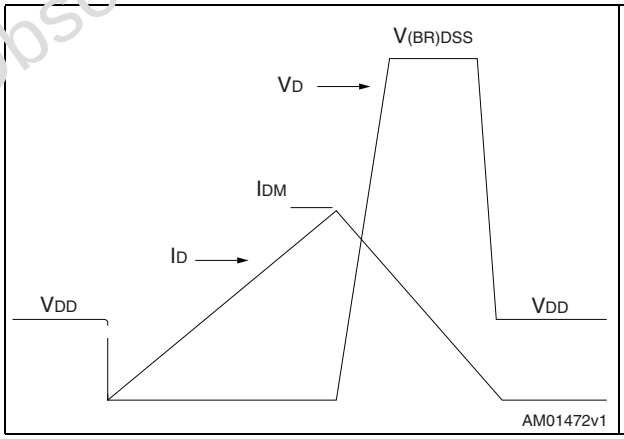
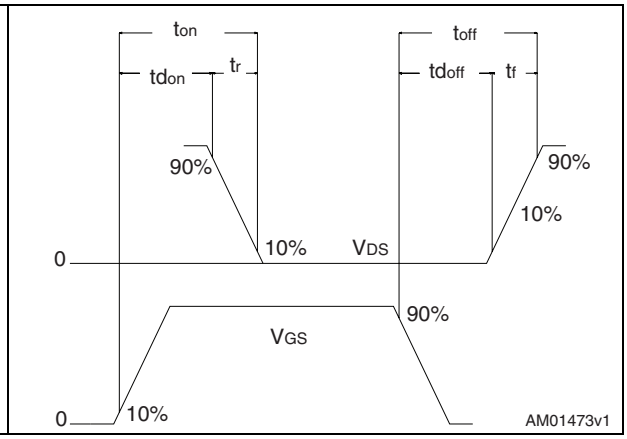


Figure 18. Switching time waveform



Obsolete Product(s) - Obsolete Product(s)

4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

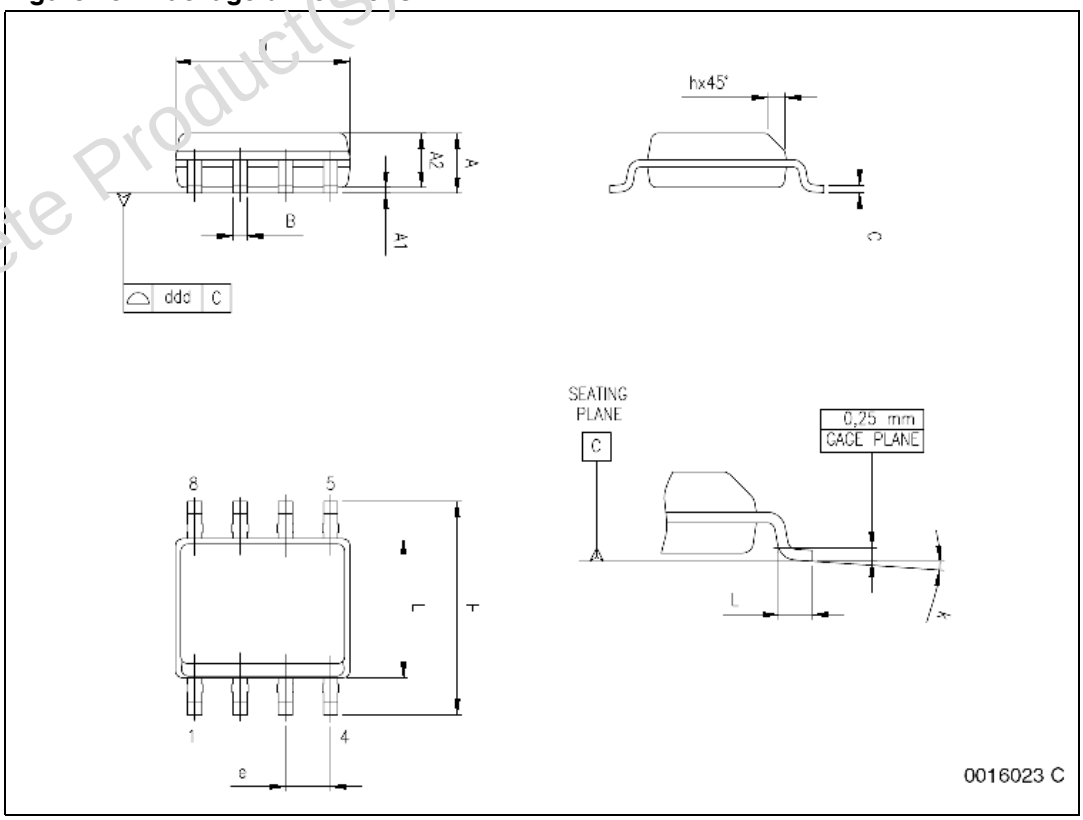
Obsolete Product(s) - Obsolete Product(s)

Table 1. SO-8 mechanical data

Dim.	mm.			inch		
	Min	Typ	Max	Min	Typ	Max
A	1.35		1.75	0.053		0.069
A1	0.10		0.25	0.004		0.010
A2	1.10		1.65	0.043		0.065
B	0.33		0.51	0.013		0.020
C	0.19		0.25	0.007		0.010
D (1)	4.80		5.00	0.189		0.197
E	3.80		4.00	0.15		0.157
e		1.27			0.050	
H	5.80		6.20	0.228		0.244
h	0.25		0.50	0.010		0.020
L	0.40		1.27	0.016		0.050
k	0° (min.), 8° (max.)					
ddd			0.10			0.004

1. Dimensions D does not include mold flash, protrusions or gate burrs. Mold flash, potrusions or gate burrs shall not exceed 0.15mm (.006inch) in total (both side).

Figure 19. Package dimensions



Obsolete Product(s) - Obsolete Product(s)

5 Revision history

Table 8. Revision history

Date	Revision	Changes
07-Apr-2010	1	First release

Obsolete Product(s) - Obsolete Product(s)

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